Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/736,859	YAO, JIE	
Examiner	Art Unit	
Fugene Lee	2815	

	SEAR	CHED	
Class	Subclass	Date	Examiner
257	656	7/21/2005	EL
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INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
searched EAST, USPAT, JPO, EPO, IEEE	7/21/2005	EL
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